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Table of Contents

Welcome from the General Co-chairs and the Program Co-chairs ix
Organizing Committee x
Program Committee xi
IEEE Computer Society TTTC: Test Technology Technical Council xii

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Keynote Talk

The Challenge of Reliability in Future Complex Systems 3
Andrea Cuomo, STMicroelectronics

Invited Talk

Extending Moore's Law into the Next Decade—The SER Challenge 7
Norbert Seifert, Intel

Session 1: Fault Effects and Self-Checking Techniques

Characterizing Laser-Induced Pulses in ICs: Methodology and Results 11
D. Leroy, S. J. Piestrak, F. Monteiro, A. Dandache, S. Rossignol, and P. Moitrel
Path (Min) Delay Faults and their Impact on Self-Checking Circuits' Operation 17
C. Metra, M. Omaña, D. Rossi, J. M. Cazeaux, and T.M. Mak
A New Self-Checking and Code-Disjoint Non-Restoring Array Divider 23
D. Marienfeld, E. S. Sogomonyan, V. Otcheretnij, and M. Gössel

Session 2: BIST Techniques

Delay Fault Localization in Test-Per-Scan BIST Using Built-In Delay Sensor 31
Swaroop Ghosh, Swarup Bhunia, Arijit Raychowdhury, and Kaushik Roy
A Partitioning Technique for Identification of Error-Capturing Scan Cells in Scan-BIST 37
Chaowen Yu, Sudhakar M. Reddy, and Irith Pomeranz
Efficient Deterministic Test Generation for BIST Schemes with LFSR Reseeding 43
Stelios Neophytou, Maria K. Michael, and Spyros Tragoudas

Session 3: Technology Robustness

Erratic Effects of Irradiation in Floating Gate Memory Cells 51
G. Cellere, A. Paccagnella, A. Visconti, and M. Bonanomi
Factors that Impact the Critical Charge of Memory Elements 57
Tino Heijmen, Damien Giot, and Philippe Roche
Prediction of Transient Induced by Neutron/Proton in CMOS Combinational Logic Cells 63
G. Hubert, A. Bougerol, F. Miller, N. Buard, L. Anghel, T. Carriere, F. Wrobel,
and R.Gaillard

Special Session 1: Memory Reliability Challenges

Organizer: C. Metra
Embedded Memory Reliability Trends and Solutions
Y. Zorian
Reliability Issues for Embedded SRAM at 90nm and Below 75
Rob Aitken
Testing Strategies for Non Volatile Memory Reliability
G. Crisenza
Towards the Methodology of On-line Diagnosis 76
Rochit Rajsuman

Special Session 2: Test and Reliability Challenges for Innovative Systems

Organizer: C. Metra
Test Challenges for 3D Circuits 79
T.M. Mak
Trends and Trade-offs in Designing Highly Robust Throughput on Chip Communication Network 80
Marcello Coppola
Floorplanning and Thermal Impact on Leakage Power and Proper Operation of Complex SOC Designs 81
Magdy S. Abadir
The Consequences of Variability in Software 82
Isaac Levendel

Panel 1

From Nuclear Reaction to System Failures: Can We Address All Levels of Soft Errors Accurately? 85
***Organizers**: Lorena Anghel, Michael Nicolaidis, and Nadine Buard*

Embedded Tutorials: Innovative Design for Robustness

Fault Tolerance Implementation within SRAM Based FPGA Designs based upon the Increased Level of Single Event Upset Susceptibility 89
Melanie Berg
Asynchronous Design: Fault Robustness and Security Characteristics 92
Marc Renaudin and Yannick Monnet

Session 4: Soft Errors and Latchup Mitigation

Combinational Logic Soft Error Analysis and Protection 99
André K. Nieuwland, Samir Jasarevic, and Goran Jerin
An Improved Technique for Reducing False Alarms Due to Soft Errors 105
Sandip Kundu and Ilia Polian
A Low-Cost Single-Event Latchup Mitigation Scheme 111
Michael Nicolaidis

Session 5: Secure Circuits

Secure Scan Techniques: A Comparison 119
David Hély, Frédérick Bancel, Marie-Lise Flottes, and Bruno Rouzeyre
Practical Evaluation of Fault Countermeasures on an Asynchronous DES Crypto Processor 125
Y. Monnet, M. Renaudin, R. Leveugle, N. Feyt, P. Moitrel, and F. M'Buwa Nzenguet
Power Attacks on Secure Hardware Based on Early Propagation of Data 131
Konrad J. Kulikowski, Mark G. Karpovsky, and Alexander Taubin

Session 6: Fault Detection Techniques

Evaluating One-Hot Encoding Finite State Machines for SEU Reliability in SRAM-based FPGAs 139
Maico Cassel and Fernanda Lima Kastensmidt
On-line Fault Detection and Location for NoC Interconnects 145
Cristian Grecu, André Ivanov, Res Saleh, Egor S. Sogomonyan, and Partha Pratim Pande
CEDA: Control-flow Error Detection through Assertions 151
Ramtilak Vemu and Jacob A. Abraham

Session 7: Analog Circuits Dependability

On-Line Error Detection in Wireless RF Transmitters Using Real-Time Streaming Data 159
V. Natarajan, G. Srinivasan, and A. Chatterjee
Phase-Locked Loop Automatic Layout Generation and Transient Fault Injection Analysis: A Case Study 165
Cristiano Lazzari, Ricardo A.L. Reis, and Lorena Anghel

Session 8: Posters

Embedded Borden 2-UED Code Checkers 173
Steffen Tarnick
A Note on Error Detection in an RSA Architecture by means of Residue Codes 176
L. Breveglieri, P. Maistri, and I. Koren
Localization of Faults in Radix-n Signed Digit Adders 178
G.C. Cardarilli, M. Ottavi, S. Pontarelli, M. Re, and A. Salsano
Embedded Scan Test with Diagnostic Features for Self-Testing SoCs 181
C. Galke, R. Kothe, S. Schultke, K. Winkler, J. Honko, and H.T. Vierhaus
Emulation-based Fault Injection in Circuits with Embedded Memories 183
Mario Garcia-Valderas, Marta Portela-Garcia, Celia López-Ongil, and Luis Entrena
Fault Tolerant System Design Method Based on Self-Checking Circuits 185
Pavel Kubalik, Petr Fišer, and Hana Kubátová
Built-in Self Repair by Reconfiguration of FPGAs 187
S. Habermann, R. Kothe, and H.T. Vierhaus
Dependability Evaluation of Transient Fault Effects in Reconfigurable Compute Fabric Devices 189
L. Sterpone and M. Violante
Evaluating SEU and Crosstalk Effects in Network-on-Chip Routers 191
Arthur Pereira Frantz, Luigi Carro, Érica Cota, and Fernanda Lima Kastensmidt
Diophantine-Equation Based Arithmetic Test Set Embedding 193
D. Nikolos, D. Kagaris, and S. Gidaros
Design of a Robust 8-Bit Microprocessor to Soft Errors 195
Rodrigo Possamai Bastos, Fernanda Lima Kastensmidt, and Ricardo Reis

Panel 2

Should Logic SER be Solved at the Circuit Level? 199
Organizers: T. M. Mak, Intel Corporation and S. Mitra, Stanford University

Session 9: Reliable Systems

DMT and DT2: Two Fault-Tolerant Architectures developed by CNES for COTS-based Spacecraft Supercomputers 203
Michel Pignol
Fault-Robust Microcontrollers for Automotive Applications 213
Riccardo Mariani, Peter Fuhrmann, and Boris Vittorelli
Contribution of Communications to Dependability in Massively-Defective General-Purpose Nanoarchitectures 219
Jacques Henri Collet, Piotr Zajac, Yves Crouzet, and Andrzej Napieralski

Session 10: Dependability Analysis

Hardware-in-the-Loop-Based Dependability Analysis of Automotive Systems 229
M. Sonza Reorda and M. Violante
A Low-Cost SEU Fault Emulation Platform for SRAM-Based FPGAs....................235
P. Kenterlis, N. Kranitis, A. Paschalis, D. Gizopoulos, and M. Psarakis
Real Time Fault Injection Using a Modified Debugging Infrastructure....................242
André V. Fidalgo, Gustavo R. Alves, and José M. Ferreira

Session 11: New Topics in Fault Detection

The Problem of On-Line Testing Methods in Approximate Data Processing 251
A. Drozd, M. Lobachev, and J. Drozd
Dynamic Fault Detection in Digital Systems Using Dynamic Voltage Scaling and Multi-Temperature Schemes....................257
M. Rodríguez-Irago, J.J. Rodríguez Andina, F. Vargas, J. Semião, I.C. Teixeira, and J.P. Teixeira
Online Testing by Protocol Decomposition....................263
Deepali Koppad, Danil Sokolov, Alex Bystrov, and Alex Yakovlev

Panel 3

Reliability in Automotive
Organizer: A. Pagni, STMicroelectronics

Special Session 3: SER Trends: Vision and Developments from European IDMs

***Organizer**: M. Nicolaidis, TIMA Laboratory*

Soft Error Rates in Deep-Submicron CMOS Technologies 271
Tino Heijmen
Trend in DRAM Soft Errors....................272
Günter Schindlbeck

Session 12: Checkers and Error Correction

Checker No-Harm Alarm Robustness 275
Daniele Rossi, Martin Omana, Cecilia Metra, and Andrea Pagni
Designing Robust Checkers in the Presence of Massive Timing Errors....................281
Frédérick Worm, Patrick Thiran, and Paolo Ienne
Error Correction in Arithmetic Operations by I/O Inversion....................287
Petros Oikonomakos and Paul Fox

Author Index 293